IN THE CLAIMS

This listing of claims will replace all prior versions and listings of claims in the application.

Listing of Claims:

1. (Currently Amended) A micro terminal (91) with electrical conduction between said micro terminal and an electrode of an electronic device or an inspection device, comprising a columnar contactor (91a, 91e) in contact with the electrode, wherein

said contactor (91a, 91c) has a spring structure that is elastically deformed by being pressed against the electrode, and said contactor (91a, 91c) has a protrusion (1t) protruding outwardly at its end in contact with the electrode, and

said protrusion (1t) is shaped to have a part of a sphere or a paraboloid of revolution.

- 2. (Currently Amended) The micro terminal according to claim 1, wherein said contactor (91a, 91c) has a spiral spring structure.
- 3. (Currently Amended) The micro terminal according to claim 1, wherein said contactor (91a, 91e) has a structure in which a plurality of meandering springs are disposed from a perimeter portion to a central portion of said contactor.
- 4. (Currently Amended) The micro terminal according to claim 1, wherein a perimeter portion of said columnar contactor (91a, 91c) has a tubular ring structure.
- 5. (Currently Amended) The micro terminal according to claim 1, wherein said micro terminal (91) has said contactor (91a, 91c) at each of opposing ends in contact with the electrode.
- 6. (Currently Amended) The micro terminal according to claim 1, wherein said protrusion (1t) has a V-shaped groove opening toward the direction in which said protrusion protrudes.
- 7. (Currently Amended) The micro terminal according to claim 1, wherein said micro terminal (91) includes nickel or a nickel alloy.
- 8. (Currently Amended) The micro terminal according to claim 1, wherein said micro terminal (91) has a coat layer including a precious metal or an alloy of a precious metal or polytetrafluoroethylene gold.

9. (Currently Amended) A method of fabricating the micro terminal according to claim 1, wherein the contactor (91a, 91e) of said micro terminal (91) is fabricated by a method including the steps of:

forming a resin mold by X-ray lithography;

forming a layer including a metal material at said resin mold on an electrically conductive substrate by electroforming;

polishing or grinding;

forming a resin mold on said layer including a metal material by lithography;

electroforming a layer including a metal material at said resin mold to form a protrusion protruding outwardly;

removing said resin molds; and

removing said electrically conductive substrate.

10. (Currently Amended) A method of fabricating the micro terminal (91) according to claim 1, wherein the contactor (91a, 91e) of said micro terminal (91) is fabricated by a method including the steps of:

forming a resin mold by a metal mold;

forming a layer including a metal material at said resin mold on an electrically conductive substrate by electroforming;

polishing or grinding;

forming a resin mold on said layer including a metal material by lithography;

electroforming a layer including a metal material at said resin mold to form a protrusion protruding outwardly;

removing said resin molds; and

removing said electrically conductive layer.

- 11. (Currently Amended) The method of fabricating the micro terminal according to claim 9 or 10, wherein said protrusion (1t) formed is provided with a V-shaped groove formed by cutting with a dicer.
- 12. (Currently Amended) A contact sheet including the micro terminal (91) according to claim 1, having a hollow electrode (91b) penetrating the sheet in a thickness direction and said

- contactor (91a, 91c) on said hollow electrode (91b), wherein said hollow electrode (91b) has a hollow portion for a spring of said contactor (91a, 91c) to make a stroke.
- 13. (Currently Amended) The contact sheet according to claim 12, wherein said hollow electrode (91b) and said contactor (91a, 91c) are joined by resistance welding.
- 14. (Currently Amended) A socket for inspection including the micro terminal (91) according to claim 1, wherein said socket is used for inspection of semiconductor in land grid array arrangement.
- 15. (Original) An inspection device including the socket according to claim 14.
- 16. (Original) A method of inspecting semiconductor using the socket according to claim 14.
- 17. (Currently Amended) A connector for installation including the micro terminal (91) according to claim 1, wherein said connector is connected to a land electrode.
- 18. (Original) An electronic device including the connector according to claim 17.
- 19. (New) The method of fabricating the micro terminal according to claim 10, wherein said protrusion formed is provided with a V-shaped groove formed by cutting with a dicer.